AMD Xilinx - XCS10-3VQG100C Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	196
Number of Logic Elements/Cells	466
Total RAM Bits	6272
Number of I/O	77
Number of Gates	10000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs10-3vqg100c

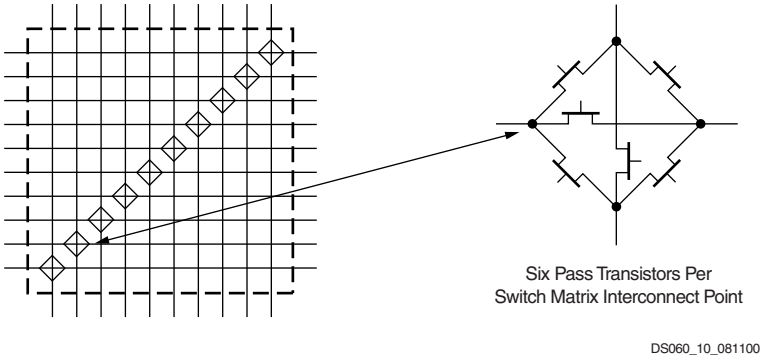


Figure 10: **Programmable Switch Matrix**

Double-Length Lines

The double-length lines consist of a grid of metal segments, each twice as long as the single-length lines: they run past two CLBs before entering a PSM. Double-length lines are grouped in pairs with the PSMs staggered, so that each line goes through a PSM at every other row or column of CLBs (see Figure 8).

There are four vertical and four horizontal double-length lines associated with each CLB. These lines provide faster signal routing over intermediate distances, while retaining routing flexibility.

Longlines

Longlines form a grid of metal interconnect segments that run the entire length or width of the array. Longlines are intended for high fan-out, time-critical signal nets, or nets that are distributed over long distances.

Each Spartan/XL device longline has a programmable splitter switch at its center. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Routing connectivity of the longlines is shown in Figure 8. The longlines also interface to some 3-state buffers which is described later in **3-State Long Line Drivers**, page 19.

I/O Routing

Spartan/XL devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines, and four longlines.

Global Nets and Buffers

The Spartan/XL devices have dedicated global networks. These networks are designed to distribute clocks and other high fanout control signals throughout the devices with minimal skew.

Four vertical longlines in each CLB column are driven exclusively by special global buffers. These longlines are in addition to the vertical longlines used for standard interconnect. In the 5V Spartan devices, the four global lines can be driven by either of two types of global buffers; Primary Global buffers (BUFGP) or Secondary Global buffers (BUFGS). Each of these lines can be accessed by one particular Primary Global buffer, or by any of the Secondary Global buffers, as shown in Figure 11. In the 3V Spartan-XL devices, the four global lines can be driven by any of the eight Global Low-Skew Buffers (BUFGLS). The clock pins of every CLB and IOB can also be sourced from local interconnect.

Figure 20 is a diagram of the Spartan/XL FPGA boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Spartan/XL devices can also be configured through the boundary scan logic. See **Configuration Through the Boundary Scan Pins**, page 37.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-state Control. Non-IOB pins have appropriate partial bit population for In or Out only. $\overline{\text{PROGRAM}}$, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-state pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).

Instruction Set

The Spartan/XL FPGA boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 12.

figuration are shown in Table 14 and Table 15.

Table 14: **Pin Functions During Configuration (Spartan Family Only)**

Configuration Mode (MODE Pin)		User Operation
Slave Serial (High)	**Master Serial (Low)**	
MODE (I)	MODE (I)	MODE
HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)
DIN (I)	DIN (I)	I/O
DOUT	DOUT	SGCK4-I/O
TDI	TDI	TDI-I/O
TCK	TCK	TCK-I/O
TMS	TMS	TMS-I/O
TDO	TDO	TDO-(O)
		ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.

Table 15: **Pin Functions During Configuration (Spartan-XL Family Only)**

CONFIGURATION MODE <M1:M0>			User Operation
Slave Serial [1:1]	**Master Serial [1:0]**	**Express [0:X]**	
M1 (High) (I)	M1 (High) (I)	M1(Low) (I)	M1
M0 (High) (I)	M0 (Low) (I)	M0 (I)	M0
HDC (High)	HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (I)
		DATA 7 (I)	I/O
		DATA 6 (I)	I/O
		DATA 5 (I)	I/O
		DATA 4 (I)	I/O
		DATA 3 (I)	I/O
		DATA 2 (I)	I/O
		DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	GCK6-I/O
TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO-(O)
		CS1	I/O
			ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.

Master Serial Mode

The Master serial mode uses an internal oscillator to generate a Configuration Clock (CCLK) for driving potential slave devices and the Xilinx serial-configuration PROM (SPROM). The CCLK speed is selectable as either 1 MHz (default) or 8 MHz. Configuration always starts at the default slow frequency, then can switch to the higher frequency during the first frame. Frequency tolerance is –50% to +25%.

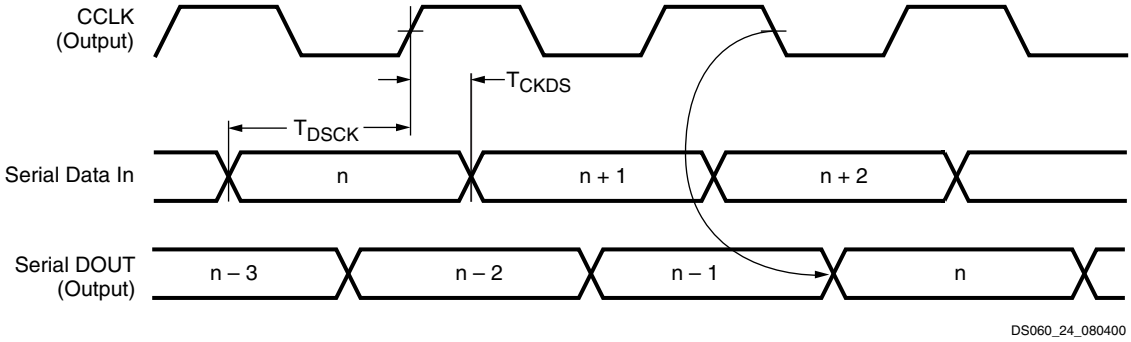
In Master Serial mode, the CCLK output of the device drives a Xilinx SPROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The FPGA accepts this data on the subsequent rising CCLK edge.

When used in a daisy-chain configuration the Master Serial FPGA is placed as the first device in the chain and is referred to as the lead FPGA. The lead FPGA presents the preamble data, and all data that overflows the lead device, on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge. See the timing diagram in Figure 24.

In the bitstream generation software, the user can specify Fast Configuration Rate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of eight. For actual timing values please refer to the specification section. Be sure that the serial PROM and slaves are fast enough to support this data rate. Earlier families such as the XC3000 series do not support the Fast Configuration Rate option.

The SPROM CE input can be driven from either $\overline{LDC}$ or DONE. Using $\overline{LDC}$ avoids potential contention on the DIN pin, if this pin is configured as user I/O, but $\overline{LDC}$ is then restricted to be a permanently High user output after configuration. Using DONE can also avoid contention on DIN, provided the Early DONE option is invoked.

Figure 25 shows a full master/slave system. The leftmost device is in Master Serial mode, all other devices in the chain are in Slave Serial mode.



	Symbol	Description	Min	Units
CCLK	T_{DSCK}	DIN setup	20	ns
	T_{CKDS}	DIN hold	0	ns

Notes:
1. At power-up, V_{CC} must rise from 2.0V to V_{CC} min in less than 25 ms, otherwise delay configuration by pulling $\overline{PROGRAM}$ Low until V_{CC} is valid.
2. Master Serial mode timing is based on testing in slave mode.

Figure 24: **Master Serial Mode Programming Switching Characteristics**

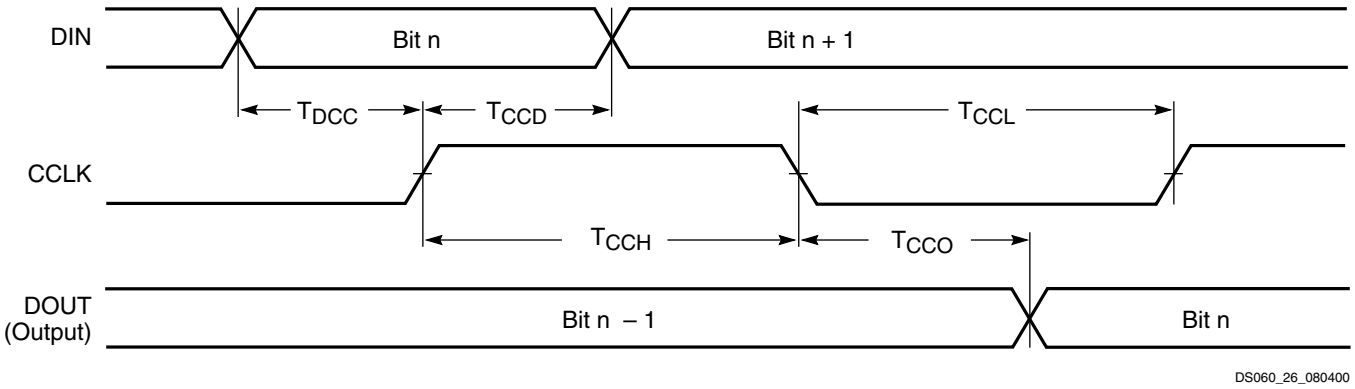
Slave Serial Mode

In Slave Serial mode, the FPGA receives serial configuration data on the rising edge of CCLK and, after loading its configuration, passes additional data out, resynchronized on the next falling edge of CCLK.

In this mode, an external signal drives the CCLK input of the FPGA (most often from a Master Serial device). The serial configuration bitstream must be available at the DIN input of the lead FPGA a short setup time before each rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal delay of 0.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

Figure 25 shows a full master/slave system. A Spartan/XL device in Slave Serial mode should be connected as shown in the third device from the left.



Symbol		Description	Min	Max	Units
T_{DCC}	CCLK	DIN setup	20	-	ns
T_{CCD}		DIN hold	0	-	ns
T_{CCO}		DIN to DOUT	-	30	ns
T_{CCH}		High time	40	-	ns
T_{CCL}		Low time	40	-	ns
F_{CC}		Frequency	-	12.5	MHz

Notes:
1. Configuration must be delayed until the $\overline{INIT}$ pins of all daisy-chained FPGAs are High.

Figure 26: **Slave Serial Mode Programming Switching Characteristics**

Express Mode (Spartan-XL Family Only)

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers (Figure 27). A CCLK frequency of 1 MHz is equivalent to a 8 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

Express mode must be specified as an option to the development system. The Express mode bitstream is not compatible with the other configuration modes (see Table 16, page 32.) Express mode is selected by a <0X> on the Mode pins (M1, M0).

The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge (Figure 28).

Pseudo Daisy Chain

Multiple devices with different configurations can be configured in a pseudo daisy chain provided that all of the devices are in Express mode. Concatenated bitstreams are used to configure the chain of Express mode devices so that each device receives a separate header. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pull-up). The status pin DOUT is pulled Low after the header is received, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the next header and configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using a development system option.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All Spartan-XL devices in Express mode are synchronized

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0](1)
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b(2)
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes(3)	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:
1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

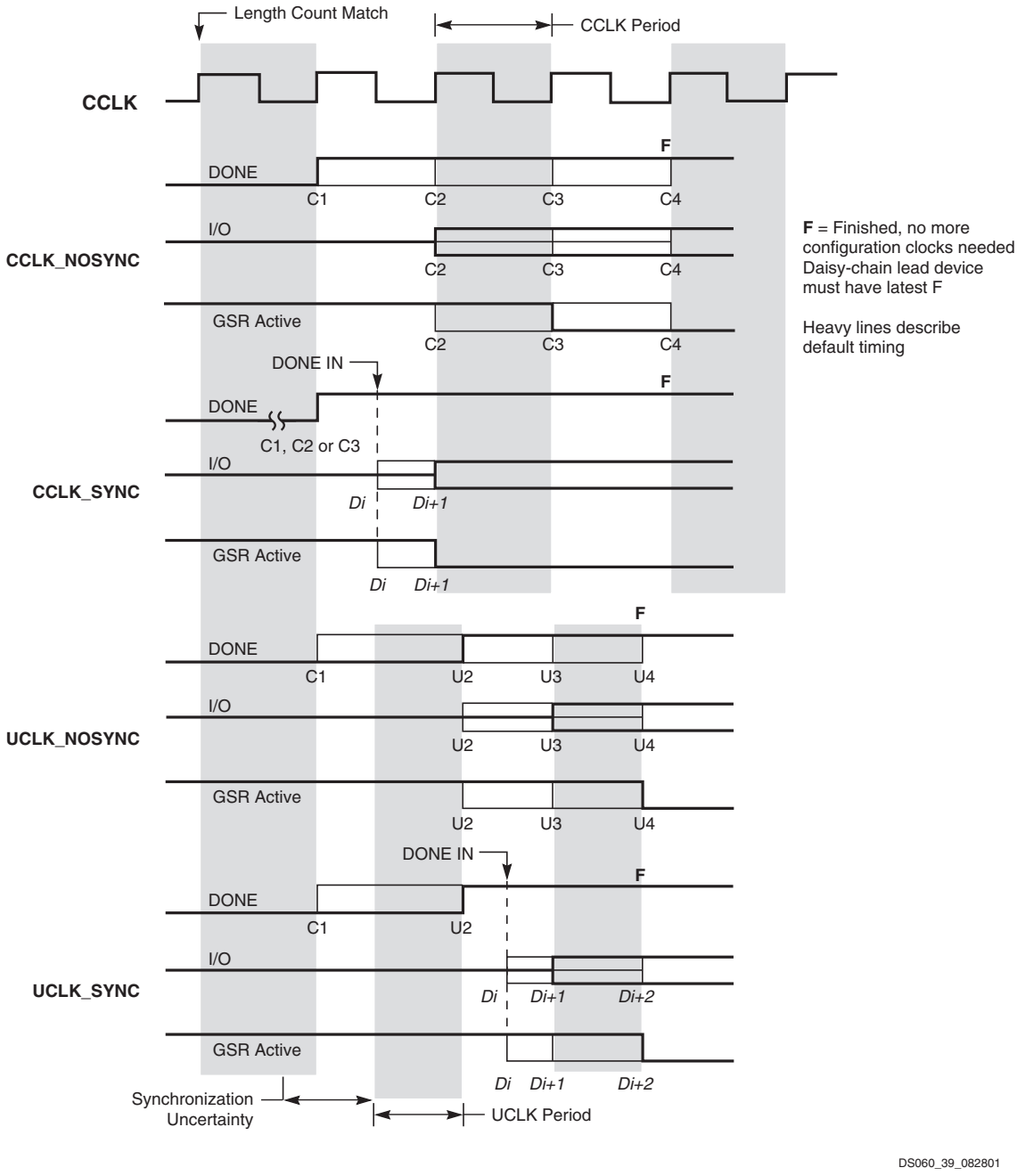


Figure 31: **Start-up Timing**

Configuration Through the Boundary Scan Pins

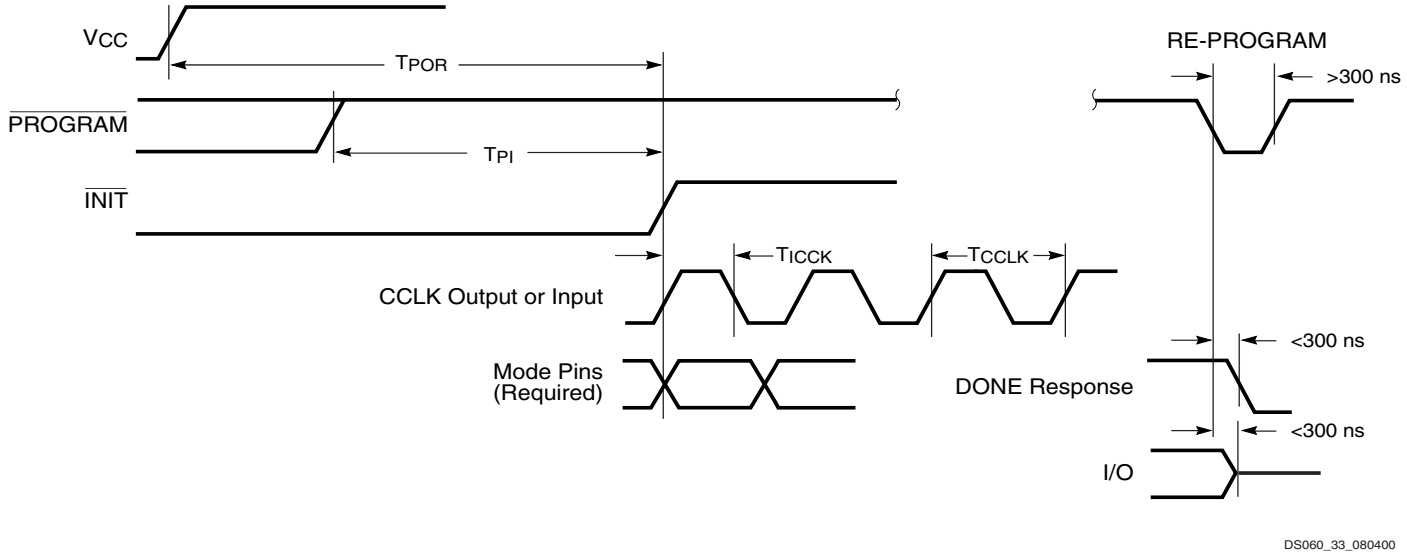
Spartan/XL devices can be configured through the boundary scan pins. The basic procedure is as follows:

- Power up the FPGA with $\overline{\text{INIT}}$ held Low (or drive the $\overline{\text{PROGRAM}}$ pin Low for more than 300 ns followed by a High while holding $\overline{\text{INIT}}$ Low). Holding $\overline{\text{INIT}}$ Low allows enough time to issue the CONFIG command to the FPGA. The pin can be used as I/O after configuration if a resistor is used to hold $\overline{\text{INIT}}$ Low.
- Issue the CONFIG command to the TMS input.
- Wait for $\overline{\text{INIT}}$ to go High.
- Sequence the boundary scan Test Access Port to the SHIFT-DR state.
- Toggle TCK to clock data into TDI pin.

The user must account for all TCK clock cycles after $\overline{\text{INIT}}$ goes High, as all of these cycles affect the Length Count compare.

For more detailed information, refer to the Xilinx application note, "*Boundary Scan in FPGA Devices*." This application note applies to Spartan and Spartan-XL devices.

Configuration Switching Characteristics



Master Mode

Symbol	Description	Min	Max	Units
T_{POR}	Power-on reset	40	130	ms
T_{PI}	Program Latency	30	200	µs per CLB column
T_{ICCK}	CCLK (output) delay	40	250	µs
T_{CCLK}	CCLK (output) period, slow	640	2000	ns
T_{CCLK}	CCLK (output) period, fast	100	250	ns

Slave Mode

Symbol	Description	Min	Max	Units
T_{POR}	Power-on reset	10	33	ms
T_{PI}	Program latency	30	200	µs per CLB column
T_{ICCK}	CCLK (input) delay (required)	4	-	µs
T_{CCLK}	CCLK (input) period (required)	80	-	ns

Spartan Family Detailed Specifications

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

Spartan Family Absolute Maximum Ratings(1)

Symbol	Description		Value	Units
V_{CC}	Supply voltage relative to GND		–0.5 to +7.0	V
V_{IN}	Input voltage relative to GND(2,3)		–0.5 to V_{CC} +0.5	V
V_{TS}	Voltage applied to 3-state output(2,3)		–0.5 to V_{CC} +0.5	V
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature	Plastic packages	+125	°C

Notes:
1. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
2. Maximum DC overshoot (above V_{CC}) or undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
3. Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to –2.0V or overshoot to +7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
4. For soldering guidelines, see the Package Information on the Xilinx website.

Spartan Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CC}	Supply voltage relative to GND, T_J = 0°C to +85°C	Commercial	4.75	5.25	V
	Supply voltage relative to GND, T_J = –40°C to +100°C(1)	Industrial	4.5	5.5	V
V_{IH}	High-level input voltage(2)	TTL inputs	2.0	V_{CC}	V
		CMOS inputs	70%	100%	V_{CC}
V_{IL}	Low-level input voltage(2)	TTL inputs	0	0.8	V
		CMOS inputs	0	20%	V_{CC}
T_{IN}	Input signal transition time		-	250	ns

Notes:
1. At junction temperatures above those listed as Recommended Operating Conditions, all delay parameters increase by 0.35% per °C.
2. Input and output measurement thresholds are: 1.5V for TTL and 2.5V for CMOS.

Spartan Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Max	Units
V_{OH}	High-level output voltage @ I_{OH} = –4.0 mA, V_{CC} min	TTL outputs	2.4	-	V
	High-level output voltage @ I_{OH} = –1.0 mA, V_{CC} min	CMOS outputs	V_{CC} – 0.5	-	V
V_{OL}	Low-level output voltage @ I_{OL} = 12.0 mA, V_{CC} min(1)	TTL outputs	-	0.4	V
		CMOS outputs	-	0.4	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		3.0	-	V
I_{CCO}	Quiescent FPGA supply current(2)	Commercial	-	3.0	mA
		Industrial	-	6.0	mA
I_L	Input or output leakage current		–10	+10	µA
C_{IN}	Input capacitance (sample tested)		-	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V (sample tested)		0.02	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 5V (sample tested)		0.02	-	mA

Notes:
1. With 50% of the outputs simultaneously sinking 12 mA, up to a maximum of 64 pins.
2. With no output current loads, no active input pull-up resistors, all package pins at V_{CC} or GND, and the FPGA configured with a Tie option.

Spartan Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade		Units
			-4	-3	
			Max	Max	
T_{PG}	From pad through Primary buffer, to any clock K	XCS05	2.0	4.0	ns
		XCS10	2.4	4.3	ns
		XCS20	2.8	5.4	ns
		XCS30	3.2	5.8	ns
		XCS40	3.5	6.4	ns
T_{SG}	From pad through Secondary buffer, to any clock K	XCS05	2.5	4.4	ns
		XCS10	2.9	4.7	ns
		XCS20	3.3	5.8	ns
		XCS30	3.6	6.2	ns
		XCS40	3.9	6.7	ns

Spartan Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-4		-3		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	3.0	-	4.0	-	ns
T_{CL}	Clock Low time	3.0	-	4.0	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.2	-	1.6	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	2.0	-	2.7	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.7	-	2.2	ns
CLB Fast Carry Logic						
T_{OPCY}	Operand inputs (F1, F2, G1, G4) to C_{OUT}	-	1.7	-	2.1	ns
T_{ASCY}	Add/Subtract input (F3) to C_{OUT}	-	2.8	-	3.7	ns
T_{INCY}	Initialization inputs (F1, F3) to C_{OUT}	-	1.2	-	1.4	ns
T_{SUM}	C_{IN} through function generators to X/Y outputs	-	2.0	-	2.6	ns
T_{BYP}	C_{IN} to C_{OUT}, bypass function generators	-	0.5	-	0.6	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop outputs Q	-	2.1	-	2.8	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	1.8	-	2.4	-	ns
T_{IHCK}	F/G inputs via H	2.9	-	3.9	-	ns
T_{HH1CK}	C inputs via H1 through H	2.3	-	3.3	-	ns
T_{DICK}	C inputs via DIN	1.3	-	2.0	-	ns
T_{ECCK}	C inputs via EC	2.0	-	2.6	-	ns
T_{RCK}	C inputs via S/R, going Low (inactive)	2.5	-	4.0	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	3.0	-	4.0	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	3.0	-	4.0	ns
Global Set/Reset						
T_{MRW}	Minimum GSR pulse width	11.5	-	13.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 50 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	166	-	125	MHz

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size[1]	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Write Operation							
T_{WCS}	Address write cycle time (clock K period)	16x2	8.0	-	11.6	-	ns
T_{WCTS}		32x1	8.0	-	11.6	-	ns
T_{WPS}	Clock K pulse width (active edge)	16x2	4.0	-	5.8	-	ns
T_{WPTS}		32x1	4.0	-	5.8	-	ns
T_{ASS}	Address setup time before clock K	16x2	1.5	-	2.0	-	ns
T_{ASTS}		32x1	1.5	-	2.0	-	ns
T_{AHS}	Address hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{AHTS}		32x1	0.0	-	0.0	-	ns
T_{DSS}	DIN setup time before clock K	16x2	1.5	-	2.7	-	ns
T_{DSTS}		32x1	1.5	-	1.7	-	ns
T_{DHS}	DIN hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{DHTS}		32x1	0.0	-	0.0	-	ns
T_{WSS}	WE setup time before clock K	16x2	1.5	-	1.6	-	ns
T_{WSTS}		32x1	1.5	-	1.6	-	ns
T_{WHS}	WE hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{WHTS}		32x1	0.0	-	0.0	-	ns
T_{WOS}	Data valid after clock K	16x2	-	6.5	-	7.9	ns
T_{WOTS}		32x1	-	7.0	-	9.3	ns
Read Operation							
T_{RC}	Address read cycle time	16x2	2.6	-	2.6	-	ns
T_{RCT}		32x1	3.8	-	3.8	-	ns
T_{ILO}	Data valid after address change (no Write Enable)	16x2	-	1.2	-	1.6	ns
T_{IHO}		32x1	-	2.0	-	2.7	ns
T_{ICK}	Address setup time before clock K	16x2	1.8	-	2.4	-	ns
T_{IHCK}		32x1	2.9	-	3.9	-	ns

Notes:
1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.

Spartan Family Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan Family Primary and Secondary Setup and Hold

Symbol	Description	Device	Speed Grade		Units
			-4	-3	
			Min	Min	
Input Setup/Hold Times Using Primary Clock and IFF					
T_{PSUF}/T_{PHF}	No Delay	XCS05	1.2 / 1.7	1.8 / 2.5	ns
		XCS10	1.0 / 2.3	1.5 / 3.4	ns
		XCS20	0.8 / 2.7	1.2 / 4.0	ns
		XCS30	0.6 / 3.0	0.9 / 4.5	ns
		XCS40	0.4 / 3.5	0.6 / 5.2	ns
T_{PSU}/T_{PH}	With Delay	XCS05	4.3 / 0.0	6.0 / 0.0	ns
		XCS10	4.3 / 0.0	6.0 / 0.0	ns
		XCS20	4.3 / 0.0	6.0 / 0.0	ns
		XCS30	4.3 / 0.0	6.0 / 0.0	ns
		XCS40	5.3 / 0.0	6.8 / 0.0	ns
Input Setup/Hold Times Using Secondary Clock and IFF					
T_{SSUF}/T_{SHF}	No Delay	XCS05	0.9 / 2.2	1.5 / 3.0	ns
		XCS10	0.7 / 2.8	1.2 / 3.9	ns
		XCS20	0.5 / 3.2	0.9 / 4.5	ns
		XCS30	0.3 / 3.5	0.6 / 5.0	ns
		XCS40	0.1 / 4.0	0.3 / 5.7	ns
T_{SSU}/T_{SH}	With Delay	XCS05	4.0 / 0.0	5.7 / 0.0	ns
		XCS10	4.0 / 0.0	5.7 / 0.0	ns
		XCS20	4.0 / 0.5	5.7 / 0.5	ns
		XCS30	4.0 / 0.5	5.7 / 0.5	ns
		XCS40	5.0 / 0.0	6.5 / 0.0	ns

Notes:

1. Setup time is measured with the fastest route and the lightest load. Hold time is measured using the furthest distance and a reference load of one clock pin per IOB/CLB.
2. IFF = Input Flip-flop or Latch

Spartan Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Setup Times - TTL Inputs(1)							
T_{ECIK}	Clock Enable (EC) to Clock (IK), no delay	All devices	1.6	-	2.1	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.5	-	2.0	-	ns
Hold Times							
T_{IKEC}	Clock Enable (EC) to Clock (IK), no delay	All devices	0.0	-	0.9	-	ns
	All Other Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays - TTL Inputs(1)							
T_{PID}	Pad to I1, I2	All devices	-	1.5	-	2.0	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.8	-	3.6	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	2.7	-	2.8	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	3.2	-	3.9	ns
Delay Adder for Input with Delay Option							
T_{Delay}	$T_{ECIKD} = T_{ECIK} + T_{Delay}$ $T_{PICKD} = T_{PICK} + T_{Delay}$ $T_{PDLI} = T_{PLI} + T_{Delay}$	XCS05	3.6	-	4.0	-	ns
		XCS10	3.7	-	4.1	-	ns
		XCS20	3.8	-	4.2	-	ns
		XCS30	4.5	-	5.0	-	ns
		XCS40	5.5	-	5.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5	-	13.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05	-	9.0	-	11.3	ns
		XCS10	-	9.5	-	11.9	ns
		XCS20	-	10.0	-	12.5	ns
		XCS30	-	10.5	-	13.1	ns
		XCS40	-	11.0	-	13.8	ns

Notes:

1. Delay adder for CMOS Inputs option: for -3 speed grade, add 0.4 ns; for -4 speed grade, add 0.2 ns.
2. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
3. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Clocks							
T_{CH}	Clock High	All devices	3.0	-	4.0	-	ns
T_{CL}	Clock Low	All devices	3.0	-	4.0	-	ns
Propagation Delays - TTL Outputs(1,2)							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.3	-	4.5	ns
T_{OKPOS}	Clock (OK to Pad, slew-rate limited	All devices	-	6.9	-	7.0	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	3.6	-	4.8	ns
T_{OPS}	Output (O) to Pad, slew-rate limited	All devices	-	7.2	-	7.3	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	3.0	-	3.8	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	6.0	-	7.3	ns
T_{TSONS}	3-state to Pad active and valid, slew-rate limited	All devices	-	9.6	-	9.8	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	2.5	-	3.8	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	2.0	-	2.7	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.0	-	0.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5		13.5		ns
T_{RPO}	Delay from GSR input to any Pad	XCS05	-	12.0	-	15.0	ns
		XCS10	-	12.5	-	15.7	ns
		XCS20	-	13.0	-	16.2	ns
		XCS30	-	13.5	-	16.9	ns
		XCS40	-	14.0	-	17.5	ns

Notes:

1. Delay adder for CMOS Outputs option (with fast slew rate option): for -3 speed grade, add 1.0 ns; for -4 speed grade, add 0.8 ns.
2. Delay adder for CMOS Outputs option (with slow slew rate option): for -3 speed grade, add 2.0 ns; for -4 speed grade, add 1.5 ns.
3. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
4. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade		Units
			-5	-4	
			Max	Max	
Global Clock to Output using OFF					
T_{ICKOF}	Fast	XCS05XL	4.6	5.2	ns
		XCS10XL	4.9	5.5	ns
		XCS20XL	5.2	5.8	ns
		XCS30XL	5.5	6.2	ns
		XCS40XL	5.8	6.5	ns
Slew Rate Adjustment					
T_{SLOW}	For Output SLOW option add	All Devices	1.5	1.7	ns

Notes:
1. Output delays are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load.
3. OFF = Output Flip Flop

Spartan-XL Family Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Setup and Hold

Symbol	Description	Device	Speed Grade		Units
			-5	-4	
			Max	Max	
Input Setup/Hold Times Using Global Clock and IFF					
T_{SUF}/T_{HF}	No Delay	XCS05XL	1.1/2.0	1.6/2.6	ns
		XCS10XL	1.0/2.2	1.5/2.8	ns
		XCS20XL	0.9/2.4	1.4/3.0	ns
		XCS30XL	0.8/2.6	1.3/3.2	ns
		XCS40XL	0.7/2.8	1.2/3.4	ns
T_{SU}/T_{H}	Full Delay	XCS05XL	3.9/0.0	5.1/0.0	ns
		XCS10XL	4.1/0.0	5.3/0.0	ns
		XCS20XL	4.3/0.0	5.5/0.0	ns
		XCS30XL	4.5/0.0	5.7/0.0	ns
		XCS40XL	4.7/0.0	5.9/0.0	ns

Notes:
1. IFF = Input Flip-Flop or Latch
2. Setup time is measured with the fastest route and the lightest load. Hold time is measured using the furthest distance and a reference load of one clock pin per IOB/CLB.

Capacitive Load Factor

Figure 35 shows the relationship between I/O output delay and load capacitance. It allows a user to adjust the specified output delay if the load capacitance is different than 50 pF. For example, if the actual load capacitance is 120 pF, add 2.5 ns to the specified delay. If the load capacitance is 20 pF, subtract 0.8 ns from the specified output delay. Figure 35 is usable over the specified operating conditions of voltage and temperature and is independent of the output slew rate control.

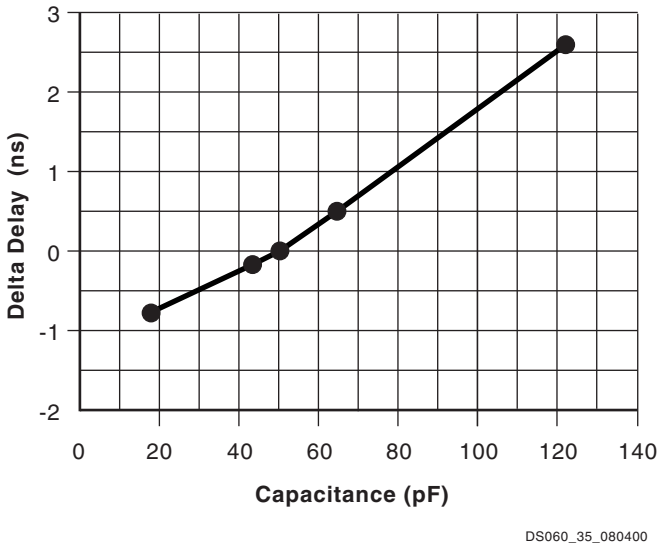


Figure 35: **Delay Factor at Various Capacitive Loads**

Table 18: **Pin Descriptions *(Continued)***

Pin Name	I/O During Config.	I/O After Config.	Pin Description
$\overline{\text{PWRDWN}}$	I	I	$\overline{\text{PWRDWN}}$ is an active Low input that forces the FPGA into the Power Down state and reduces power consumption. When $\overline{\text{PWRDWN}}$ is Low, the FPGA disables all I/O and initializes all flip-flops. All inputs are interpreted as Low independent of their actual level. VCC must be maintained, and the configuration data is maintained. $\overline{\text{PWRDWN}}$ halts configuration if asserted before or during configuration, and re-starts configuration when removed. When $\overline{\text{PWRDWN}}$ returns High, the FPGA becomes operational by first enabling the inputs and flip-flops and then enabling the outputs. $\overline{\text{PWRDWN}}$ has a default internal pull-up resistor.
User I/O Pins That Can Have Special Functions			
TDO	O	O	If boundary scan is used, this pin is the Test Data Output. If boundary scan is not used, this pin is a 3-state output without a register, after configuration is completed. To use this pin, place the library component TDO instead of the usual pad symbol. An output buffer must still be used.
TDI, TCK, TMS	I	I/O or I (JTAG)	If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. In this case, they must be called out by special library elements. To use these pins, place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used.
HDC	O	I/O	High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin.
$\overline{\text{LDC}}$	O	I/O	Low During Configuration ($\overline{\text{LDC}}$) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, $\overline{\text{LDC}}$ is a user-programmable I/O pin.
$\overline{\text{INIT}}$	I/O	I/O	Before and during configuration, $\overline{\text{INIT}}$ is a bidirectional signal. A 1 kΩ to 10 kΩ external pull-up resistor is recommended. As an active Low open-drain output, $\overline{\text{INIT}}$ is held Low during the power stabilization and internal clearing of the configuration memory. As an active Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 30 to 300 µs after $\overline{\text{INIT}}$ has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, $\overline{\text{INIT}}$ is a user-programmable I/O pin.
PGCK1 - PGCK4 (Spartan)	Weak Pull-up	I or I/O	Four Primary Global inputs each drive a dedicated internal global net with short delay and minimal skew. If not used to drive a global buffer, any of these pins is a user-programmable I/O. The PGCK1-PGCK4 pins drive the four Primary Global Buffers. Any input pad symbol connected directly to the input of a BUFGP symbol is automatically placed on one of these pins.

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84[4]	VQ100	CS144[2,4]	TQ144	Bndry Scan
I/O	P80	P81	A10	P116	17
GND	-	-	C9	P118	-
I/O	-	-	B9	P119	20
I/O	-	-	A9	P120	23
I/O	P81	P82	D8	P121	26
I/O	P82	P83	C8	P122	29
I/O	-	P84	B8	P123	32
I/O	-	P85	A8	P124	35
I/O	P83	P86	B7	P125	38
I/O	P84	P87	A7	P126	41
GND	P1	P88	C7	P127	-

Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS10XL is not part of the Boundary Scan chain. For the XCS10XL, subtract 1 from all Boundary Scan numbers from GCK3 on (175 and higher).
4. PC84 and CS144 packages discontinued by PDN2004-01

Additional XCS10/XL Package Pins

TQ144					
Not Connected Pins					
P117	-	-	-	-	-
5/5/97					

CS144					
Not Connected Pins					
D9	-	-	-	-	-
4/28/99					

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144[2,4]	TQ144	PQ208	Bndry Scan
VCC	P89	D7	P128	P183	-
I/O	P90	A6	P129	P184	62
I/O	P91	B6	P130	P185	65
I/O	P92	C6	P131	P186	68
I/O	P93	D6	P132	P187	71
I/O	-	-	-	P188	74
I/O	-	-	-	P189	77
I/O	P94	A5	P133	P190	80
I/O	P95	B5	P134	P191	83
VCC[2]	-	-	-	P192	-
I/O	-	C5	P135	P193	86
I/O	-	D5	P136	P194	89
GND	-	A4	P137	P195	-
I/O	-	-	-	P196	92
I/O	-	-	-	P197	95
I/O	-	-	-	P198	98
I/O	-	-	-	P199	101
I/O	P96	B4	P138	P200	104
I/O	P97	C4	P139	P201	107
I/O	-	A3	P140	P204	110
I/O	-	B3	P141	P205	113
I/O	P98	C3	P142	P206	116

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144[2,4]	TQ144	PQ208	Bndry Scan
I/O, SGCK1[1], GCK8[2]	P99	A2	P143	P207	119
VCC	P100	B2	P144	P208	-
GND	P1	A1	P1	P1	-
I/O, PGCK1[1], GCK1[2]	P2	B1	P2	P2	122
I/O	P3	C2	P3	P3	125
I/O	-	C1	P4	P4	128
I/O	-	D4	P5	P5	131
I/O, TDI	P4	D3	P6	P6	134
I/O, TCK	P5	D2	P7	P7	137
I/O	-	-	-	P8	140
I/O	-	-	-	P9	143
I/O	-	-	-	P10	146
I/O	-	-	-	P11	149
GND	-	D1	P8	P13	-
I/O	-	E4	P9	P14	152
I/O	-	E3	P10	P15	155
I/O, TMS	P6	E2	P11	P16	158
I/O	P7	E1	P12	P17	161
VCC[2]	-	-	-	P18	-
I/O	-	-	-	P19	164
I/O	-	-	-	P20	167

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100[5]	TQ144	PQ208	PQ240	BG256[5]	CS280[2,5]	Bndry Scan
I/O	-	-	-	P190	B16	A15	23
I/O	-	P117	P166	P191	A16	E14	26
I/O	-	-	P167	P192	C15	C14	29
I/O	-	-	P168	P193	B15	B14	32
I/O	-	-	P169	P194	A15	D14	35
GND	-	P118	P170	P196	GND[4]	GND[4]	-
I/O	-	P119	P171	P197	B14	A14	38
I/O	-	P120	P172	P198	A14	C13	41
I/O	-	-	-	P199	C13	B13	44
I/O	-	-	-	P200	B13	A13	47
VCC	-	-	P173	P201	VCC[4]	D13	-
I/O	P82	P121	P174	P202	C12	B12	50
I/O	P83	P122	P175	P203	B12	D12	53
I/O	-	-	P176	P205	A12	A11	56
I/O	-	-	P177	P206	B11	B11	59
I/O	P84	P123	P178	P207	C11	C11	62
I/O	P85	P124	P179	P208	A11	D11	65
I/O	P86	P125	P180	P209	A10	A10	68
I/O	P87	P126	P181	P210	B10	B10	71
GND	P88	P127	P182	P211	GND[4]	GND[4]	-

2/8/00

Notes:
1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS30XL is not part of the Boundary Scan chain. For the XCS30XL, subtract 1 from all Boundary Scan numbers from GCK3 on (295 and higher).
4. Pads labeled GND[4] or V_{CC}[4] are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package, and VQ100 and BG256 packages for XCS30 only, discontinued by PDN2004-01

Additional XCS30/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

2/12/98

GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-
Not Connected Pins					
A7	A13	C8	D12	H20	J3
J4	M4	M19	V9	W9	W13
Y13	-	-	-	-	-

6/4/97

BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-

CS280

VCC Pins					
A1	A7	C10	C17	D13	G1
G1	G19	K2	K17	M4	N16
T7	U3	U10	U17	W13	-
GND Pins					